PCN Nu	mber:	201	81207	7002.1					PC	N Dat	e: Dec 18, 20	18	
Title:	Assemb	ly sit	e mov	e from A	Amko	or P1 to T	Taiwan	for Se	lect	Device	es		
Customer Contact: PCN Manager Dept: Quality Services													
Propose	ip Date: Mar 18, 2		, 201	019 Estimate		mated Ava	d Sample Date provided at sample request						
Change	Type:			•									
	embly Sit	е			D	esign				Wafe	r Bump Site		
Assembly Process				Data Sheet				Wafer Bump Material					
Ass	embly Ma	teria	ls		Pa	Part number change			Wafer Bump Process				
Mec	hanical S	pecification			Te	Test Site			Wafer Fab Site				
🛛 Pac	king/Ship	ping,	/Label	eling 📃 Test		est Proces	st Process			Wafer Fab Materials			
										Wafe	r Fab Process		
						PCN D	etails						
Descrip	tion of C	nang	ge:				Assemble	lu sita			Analyse D1 to		
Texas Instruments Incorporated is announcing the Assembly site move from Amkor P1 to TI Taiwan for select devices listed in the "Product Affected" Section. Current assembly sites and Material differences are as follows.													
Assem	bly Site	A	sseml	bly Site	Orig	in Ass	embly C	ountr	y C	ode	Assembly Site	e City	
Amk	kor P1			AKR			Р	HL			Muntinlupa		
											Chung Ho, N	lew	
	aiwan			IAI			1	WN			Taipei City	/	
Matoria	l Difforo	nces											
Flatenia	Differe		<u>Λ</u> m	kor D1		TI Tai	wan						
Mount	compound	4	101	275201		4147	000						
Mount		1	1013/5281			4147858		-					
Mold c	Mold compound 101323		323397	4211880									
Lead	l Finish		Matte Sn			NiPdAu							
Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.													
Amkor P1 discontinuing SOIC 28DW package production line Continuity of supply.													
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):													
None													
Anticipated impact on Material Declaration													
No Impact to the Material Declarations or Product Content reports are driven from													
Material Declaration production data and will be available following the production					tion								
release. Upon production release the revised reports can be				be									
obtained from the <u>TI Eco-Info website</u> . There is no impact to			t to the										
material meeting current regulatory compliance requirements				ents									
Changes to product identification resulting from this PCN:													
Sample Product Shipping Label (not actual product label)													
Assembly Site													
Amkor P1 Assembly Site Origin (22L) ASO: AKR													
TI Taiw	an		Ass	embly Si	te Oi	rigin (22L	)	ASO	): T/	AI			



# Qualification Report

### COP8SGE728M8/NOPB COP8SGR728M8/NOPB SOIC 28DW Device Qual in TAI

Approve Date 07-Dec-2018

Data Displayed as: Number of lots / Total sample size / Total failed					
Туре	Test Name / Condition	Duration	Qual Device: COP8SGE728M8/NOPB	QBS Package Reference: <u>SM72295MA/NOPB</u>	QBS Package Reference: <u>TPIC6C596DRQ1</u>
AC	Autoclave 121C	96HRS		3/229/0	3/231/0
HAST	Biased HAST, 130C/85%RH	96 Hours		-	3/231/0
HTOL	Life Test, 125C	1000 Hours		-	3/231/0
HTSL	High Temp Storage Bake 150C	1000 Hours		-	3/135/0
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	1/Pass	3/Pass	3/Pass
тс	Temperature Cycle, - 65/150C	500 Cycles		3/231/0	3/231/0
CDM	ESD - CDM	1500 V	2/6/0		
ED	Electrical Characterization	Per Datasheet Parameters	1/30/0		

**Qualification Results** 

- QBS: Qual By Similarity

- Qual Device COP8SGE728M8/NOPB is qualified at LEVEL3-260CG

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

### Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

THIS INFORMATION RELATING TO QUALITY AND RELIABILITY IS PROVIDED "AS IS." Product information detailed in this report may not accurately reflect TI's current product materials, processes and testing used in the construction of the TI products. Customers are solely responsible to conduct sufficient engineering and additional qualification testing to determine whether a device is suitable for use in their applications. Using TI products outside limits stated in TI's datasheet may void TI's warranty. See TI's Terms of Sale at "http://www.ti.com/lsds/ti/legal/termsofsale.page"

# Qualification Report SM72295MA TITL Offload Qualification Report

Approve Date 06-Dec-2018

## **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: <u>SM72295MA/NOPB</u>	QBS Package Reference: <u>TPIC6C596DRQ1</u>	
AC	Autoclave 121C	96HRS	3/229/0	3/231/0	
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	
HTOL	Life Test, 125C	1000 Hours	-	3/231/0	
HTSL	High Temp Storage Bake 150C	1000 Hours	-	3/135/0	
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	3/Pass	3/Pass	
тс	Temperature Cycle, -65/150C	500 Cycles	3/231/0	3/231/0	

- QBS: Qual By Similarity

- Qual Device SM72295MA/NOPB is qualified at LEVEL3-260CG

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

### Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

THIS INFORMATION RELATING TO QUALITY AND RELIABILITY IS PROVIDED "AS IS." Product information detailed in this report may not accurately reflect TI's current product materials, processes and testing used in the construction of the TI products. Customers are solely responsible to conduct sufficient engineering and additional qualification testing to determine whether a device is suitable for use in their applications. Using TI products outside limits stated in TI's datasheet may void TI's warranty. See TI's Terms of Sale at "http://www.ti.com/lsds/ti/legal/termsofsale.page"

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